## Search Notes



| Application/Control No. | Applicant(s)/Patent Under Reexamination |  |
|-------------------------|---|--|
| 10075471                | AYARS ET AL.                            |  |
| Examiner                | Art Unit                                |  |
| Paliwal, Yogesh         | 2135                                    |  |

## **SEARCHED**

| Class | Subclass      | Date    | Examiner |
|-------|---------------|---------|----------|
| 380   | 201           | 5/23/07 | PWK      |
| 713   | 165, 194      | 5/23/07 | PWK      |
| 705   | 57            | 5/23/07 | PWK      |
| 713   | 153, 157, 166 | 11/6/07 | PWK      |

## **SEARCH NOTES**

| Search Notes   | Date      | Examiner |
|--|-----------|----------|
| 380/210 and (digital with content with type)                     | 5/23/07   | PWK      |
| IEEE   | 11/6/07   | PWK      |
| East text search   | 11/6/07   | PWK      |
| Inventor name search in East                                     | 6/18/2008 | YP       |
| (713/189,194,150,155,156,157,168,175,177) + Keywords- see search | 6/18/2008 | YP       |
| history printout   |           |          |
| (726/2,16,17,20,26,27) + keywords- see search history printout   | 6/18/2008 | YP       |
| (380/200,201,210) + keywords - see search history printout       | 6/18/2008 | YP       |
| (705/59) + keywords- see search history prinout                  | 6/18/2008 | YP       |
| Databse search: Google- see search history prinout               | 6/18/2008 | YP       |

| INITED | CEDEN | JCF SF | $\Lambda$ D $\Gamma$ U |
|--------|-------|--------|------------------------|
|        |       |        |                        |

| Class | Subclass | Date | Examiner |
|-------|----------|------|----------|
|       |          |      |          |

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